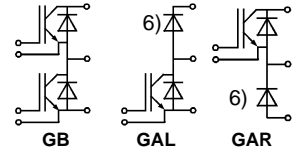


SEMİTRANS® M IGBT Modules

SKM 100 GB 123 D
SKM 100 GAL 123 D ⁶⁾
SKM 100 GAR 123 D ⁶⁾



SEMİTRANS 2



Features

- MOS input (voltage controlled)
- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to $6 \cdot I_{cnom}$
- Latch-up free
- Fast & soft inverse CAL diodes⁸⁾
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (10 mm) and creepage distances (20 mm).

Typical Applications: → B 6 - 45

- Switching (not for linear use)

¹⁾ $T_{case} = 25 \text{ }^\circ\text{C}$, unless otherwise specified

²⁾ $I_F = -I_C$, $V_R = 600 \text{ V}$, $-di/dt = 800 \text{ A}/\mu\text{s}$, $V_{GE} = 0 \text{ V}$

³⁾ Use $V_{GEOFF} = -5 \dots -15 \text{ V}$

⁵⁾ See fig. 2 + 3; $R_{Goff} = 15 \text{ } \Omega$

⁶⁾ The free-wheeling diodes of the GAL and GAR types have the data of the inverse diodes of SKM 150 GB 123 D

⁷⁾ $V_{isol} = 4000 \text{ V}_{rms}$ on request

⁸⁾ CAL = Controlled Axial Lifetime Technology.

Cases and mech. data → B 6 - 46

Absolute Maximum Ratings		Values	Units
Symbol	Conditions ¹⁾		
V_{CES}		1200	V
V_{CGR}	$R_{GE} = 20 \text{ k}\Omega$	1200	V
I_C	$T_{case} = 25/80 \text{ }^\circ\text{C}$	100 / 75	A
I_{CM}	$T_{case} = 25/80 \text{ }^\circ\text{C}$; $t_p = 1 \text{ ms}$	200 / 150	A
V_{GES}		± 20	V
P_{tot}	per IGBT, $T_{case} = 25 \text{ }^\circ\text{C}$	625	W
T_{j} , (T_{stg})		$-40 \dots +150 (125)$	$^\circ\text{C}$
V_{isol}	AC, 1 min.	2500 ⁷⁾	V
humidity	DIN 40 040	Class F	
climate	DIN IEC 68 T.1	55/150/56	
Inverse Diode			FWD ⁶⁾
$I_F = -I_C$	$T_{case} = 25/80 \text{ }^\circ\text{C}$	95 / 65	130 / 90
$I_{FM} = -I_{CM}$	$T_{case} = 25/80 \text{ }^\circ\text{C}$; $t_p = 1 \text{ ms}$	200 / 150	200 / 150
I_{FSM}	$t_p = 10 \text{ ms}$; \sin ; $T_j = 150 \text{ }^\circ\text{C}$	720	1100
I^2t	$t_p = 10 \text{ ms}$; $T_j = 150 \text{ }^\circ\text{C}$	2600	6000

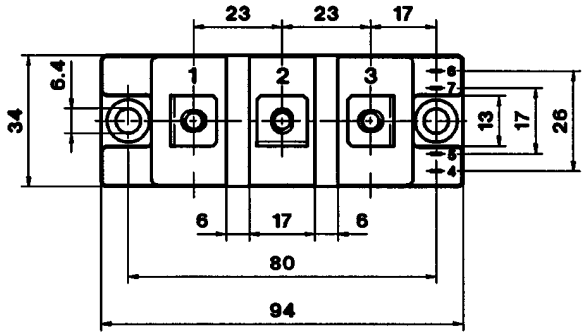
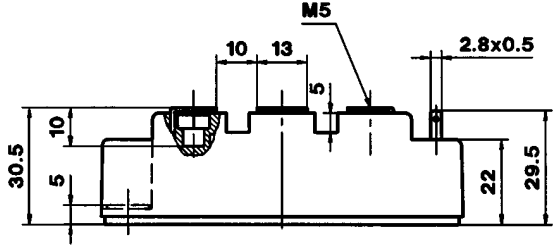
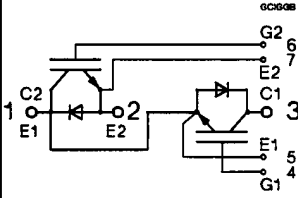
Characteristics		min.	typ.	max.	Units
Symbol	Conditions ¹⁾				
$V_{(BR)CES}$	$V_{GE} = 0$, $I_C = 4 \text{ mA}$	$\geq V_{CES}$	–	–	V
$V_{GE(th)}$	$V_{GE} = V_{CES}$, $I_C = 2 \text{ mA}$	4,5	5,5	6,5	V
I_{CES}	$V_{GE} = 0$ } $T_j = 25 \text{ }^\circ\text{C}$		0,1	1,5	mA
		$V_{CE} = V_{CES}$ } $T_j = 125 \text{ }^\circ\text{C}$	–	6	–
I_{GES}	$V_{GE} = 20 \text{ V}$, $V_{CE} = 0$	–	–	300	nA
V_{CESat}	$I_C = 75 \text{ A}$ } $V_{GE} = 15 \text{ V}$; }	–	2,5(3,1)	3(3,7)	V
V_{CESat}	$I_C = 100 \text{ A}$ } $T_j = 25 (125) \text{ }^\circ\text{C}$ }	–	2,8(3,6)	–	V
g_{fs}	$V_{CE} = 20 \text{ V}$, $I_C = 75 \text{ A}$	31	–	–	S
CCHC	per IGBT	–	–	350	pF
C_{ies}	$V_{GE} = 0$	–	5	6,6	nF
C_{oes}	$V_{CE} = 25 \text{ V}$	–	720	900	pF
C_{res}	$f = 1 \text{ MHz}$	–	380	500	pF
LCE		–	–	30	nH
$t_{d(on)}$	$V_{CC} = 600 \text{ V}$	–	30	60	ns
t_r	$V_{GE} = +15 \text{ V}$, $-15 \text{ V}^3)$	–	70	140	ns
$t_{d(off)}$	$I_C = 75 \text{ A}$, ind. load	–	450	600	ns
t_f	$R_{Gon} = R_{Goff} = 15 \text{ } \Omega$	–	70	90	ns
$E_{on}^5)$	$T_j = 125 \text{ }^\circ\text{C}$	–	10	–	mWs
$E_{off}^5)$		–	8	–	mWs
Inverse Diode ⁸⁾					
$V_F = V_{EC}$	$I_F = 75 \text{ A}$ } $V_{GE} = 0 \text{ V}$; }	–	2,0(1,8)	2,5	V
$V_F = V_{EC}$	$I_F = 100 \text{ A}$ } $T_j = 25 (125) \text{ }^\circ\text{C}$ }	–	2,25(2,05)	–	V
V_{TO}	$T_j = 125 \text{ }^\circ\text{C}$	–	–	1,2	V
r_T	$T_j = 125 \text{ }^\circ\text{C}$	–	12	15	m Ω
I_{RRM}	$I_F = 75 \text{ A}$; $T_j = 25 (125) \text{ }^\circ\text{C}^2)$	–	27(40)	–	A
Q_{rr}	$I_F = 75 \text{ A}$; $T_j = 25 (125) \text{ }^\circ\text{C}^2)$	–	3(10)	–	μC
FWD of types "GAL", "GAR" ⁸⁾					
$V_F = V_{EC}$	$I_F = 75 \text{ A}$ } $V_{GE} = 0 \text{ V}$; }	–	1,85(1,6)	2,2	V
$V_F = V_{EC}$	$I_F = 100 \text{ A}$ } $T_j = 25 (125) \text{ }^\circ\text{C}$ }	–	2,0(1,8)	–	V
V_{TO}	$T_j = 125 \text{ }^\circ\text{C}$	–	–	1,2	V
r_T	$T_j = 125 \text{ }^\circ\text{C}$	–	9	11	m Ω
I_{RRM}	$I_F = 75 \text{ A}$; $T_j = 25 (125) \text{ }^\circ\text{C}^2)$	–	30(45)	–	A
Q_{rr}	$I_F = 75 \text{ A}$; $T_j = 25 (125) \text{ }^\circ\text{C}^2)$	–	3,5(11)	–	μC
Thermal Characteristics					
R_{thjc}	per IGBT	–	–	0,2	$^\circ\text{C}/\text{W}$
R_{thjc}	per diode / FWD "GAL"; "GAR"	–	–	0,50/0,36	$^\circ\text{C}/\text{W}$
R_{thch}	per module	–	–	0,05	$^\circ\text{C}/\text{W}$

SEMISTRANS 2

Case D 61
 UL Recognized
 File no. E 63 532

CASED61

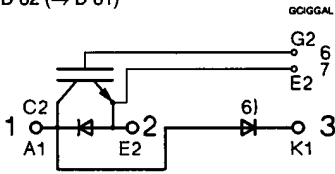
SKM 100 GB 123 D
SKM 100 GB 173 D



Dimensions in mm

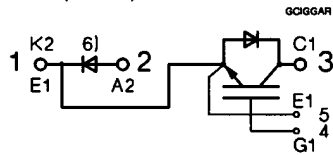
SKM 100 GAL 123 D

Case D 62 (→ D 61)



SKM 100 GAR 123 D

Case D 63 (→ D 61)



Case outline and circuit diagrams

Mechanical Data		Values			Units
Symbol	Conditions	min.	typ.	max.	
M ₁	to heatsink, SI Units (M6)	3	-	5	Nm
	to heatsink, US Units	27	-	44	lb.in.
M ₂	for terminals, SI Units (M5)	2,5	-	5	Nm
	for terminals US Units	22	-	44	lb.in.
a		-	-	5x9,81	m/s ²
w		-	-	250	g

This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.

Eight devices are supplied in one SEMIBOX A without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMISTRANS 2). Larger packing units of 20 and 42 pieces are used if suitable

Accessories → page B 6 - 4.
 SEMIBOX → page C - 1.

⁶⁾ Freewheeling diode → page B 6 - 41, remark 6.